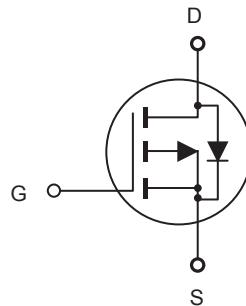


P-Channel Enhancement Mode Field Effect Transistor

PRELIMINARY

FEATURES

- -60V, -20A, $R_{DS(ON)} = 48m\Omega$ @ $V_{GS} = -10V$.
 $R_{DS(ON)} = 62m\Omega$ @ $V_{GS} = -4.5V$.
- Super high dense cell design for extremely low $R_{DS(ON)}$.
- High power and current handing capability.
- RoHS compliant.
- TO-251 & TO-252 package.

**ABSOLUTE MAXIMUM RATINGS** $T_C = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	V_{DS}	-60	V
Gate-Source Voltage	V_{GS}	± 30	V
Drain Current-Continuous	I_D	-20	A
Drain Current-Pulsed ^a	I_{DM}	-80	A
Maximum Power Dissipation @ $T_C = 25^\circ C$ - Derate above $25^\circ C$	P_D	36 0.29	W W/ $^\circ C$
Operating and Store Temperature Range	T_J, T_{stg}	-55 to 150	$^\circ C$

Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	R_{JC}	3.5	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient	R_{JA}	50	$^\circ C/W$



CED6405/CEU6405

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-60			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -60\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{\text{GS}} = 30\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{\text{GS}} = -30\text{V}, V_{\text{DS}} = 0\text{V}$			-100	nA
On Characteristics^b						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = -250\mu\text{A}$	-1		-3	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = -10\text{V}, I_D = -10\text{A}$		39	48	$\text{m}\Omega$
		$V_{\text{GS}} = -4.5\text{V}, I_D = -5\text{A}$		48	62	$\text{m}\Omega$
Dynamic Characteristics^c						
Input Capacitance	C_{iss}	$V_{\text{DS}} = -25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		1320		pF
Output Capacitance	C_{oss}			125		pF
Reverse Transfer Capacitance	C_{rss}			80		pF
Switching Characteristics^c						
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -48\text{V}, I_D = -20\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GEN}} = 6\Omega$		13		ns
Turn-On Rise Time	t_r			8		ns
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			48		ns
Turn-Off Fall Time	t_f			15		ns
Total Gate Charge	Q_g	$V_{\text{DS}} = -48\text{V}, I_D = -20\text{A}, V_{\text{GS}} = -10\text{V}$		26		nC
Gate-Source Charge	Q_{gs}			3		nC
Gate-Drain Charge	Q_{gd}			9		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current	I_S				-20	A
Drain-Source Diode Forward Voltage ^b	V_{SD}	$V_{\text{GS}} = 0\text{V}, I_S = -9\text{A}$			-1.5	V

Notes : □

a.Repetitive Rating : Pulse width limited by maximum junction temperature.

b.Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.□

c.Guaranteed by design, not subject to production testing.□

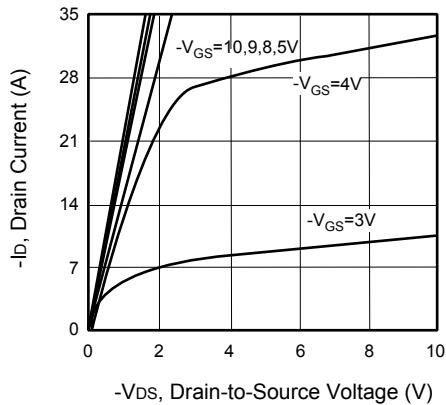


Figure 1. Output Characteristics

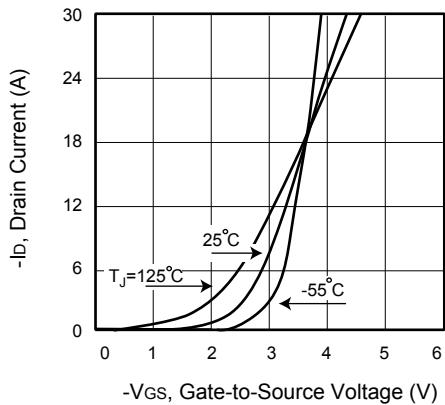


Figure 2. Transfer Characteristics

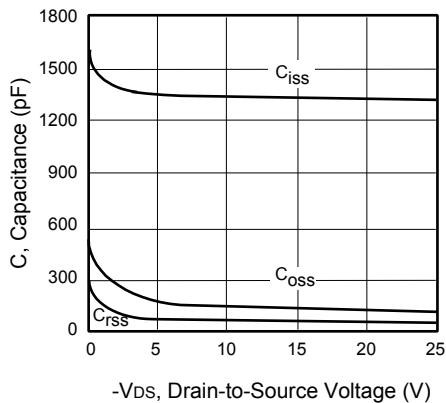


Figure 3. Capacitance

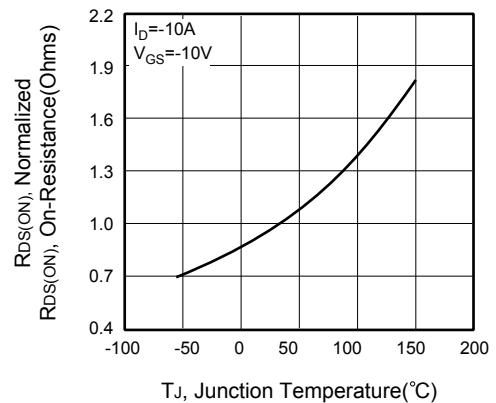


Figure 4. On-Resistance Variation with Temperature

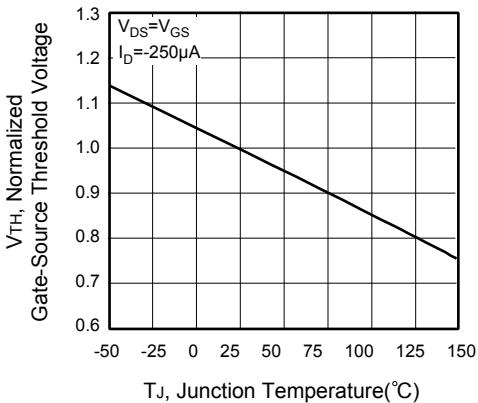


Figure 5. Gate Threshold Variation with Temperature

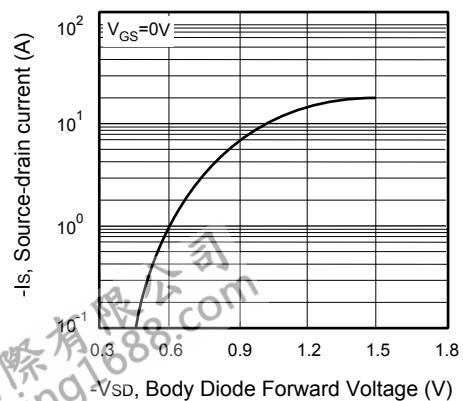


Figure 6. Body Diode Forward Voltage Variation with Source Current

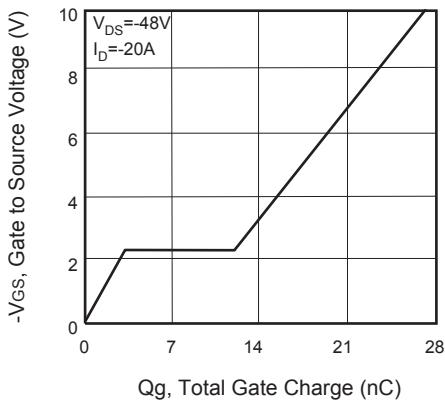
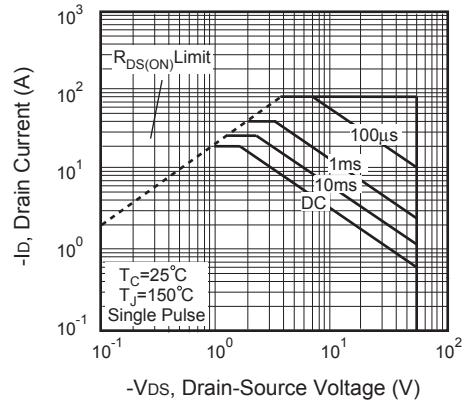
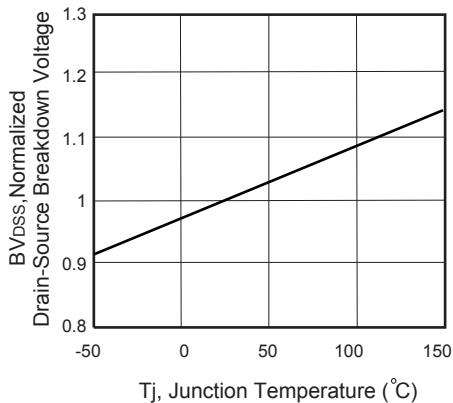


Figure 7. Gate Charge



**Figure 8. Maximum Safe
Operating Area**



**Figure 9. Breakdown Voltage Variation
VS Temperature**

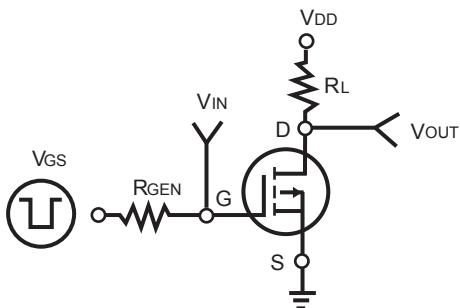


Figure 10. Switching Test Circuit

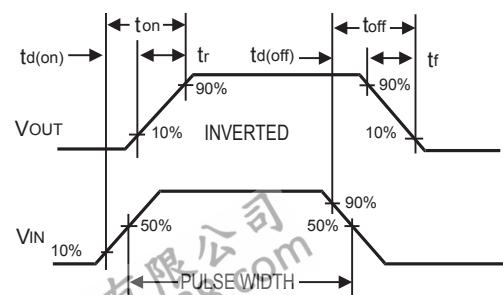
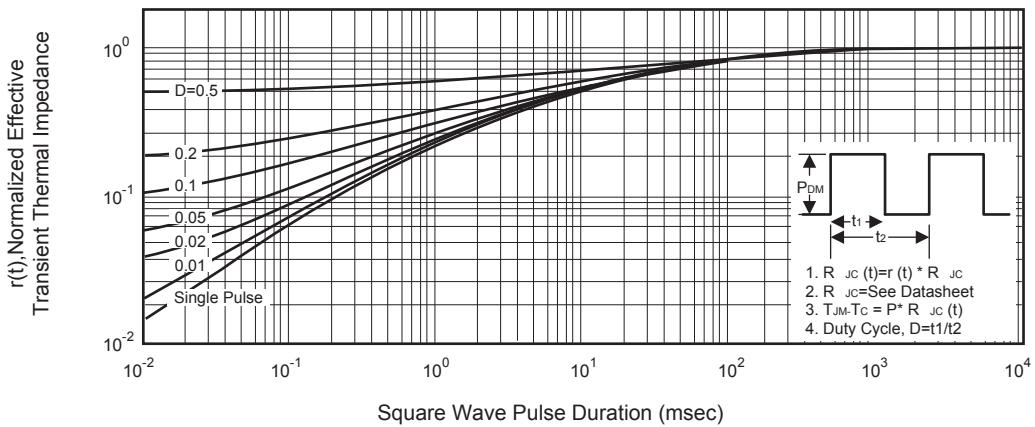


Figure 11. Switching Waveforms

**Figure 12. Normalized Thermal Transient Impedance Curve**